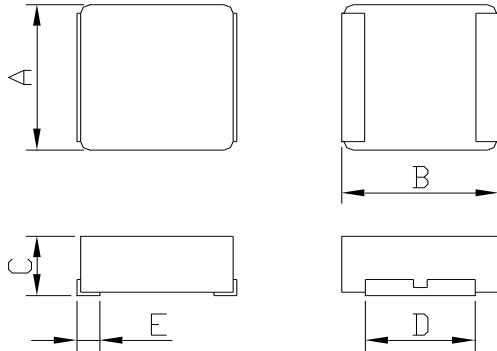


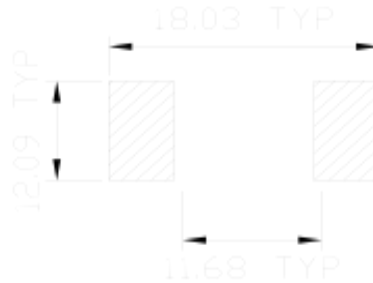
ITEM P/N	ESPA-1770-SERIES	TEST INSTRUMENT	Zentech-3305 / Zentech502BC
PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V

PACKING DIMENSIONS (mm)

1770 SERIES	Dimensions
A	17.15 MAX
B	18.0 ± 0.3
C	7.0 MAX
D	11.94 ± 0.3
E	2.70 ± 0.4

EXPLANATION OF PART NUMBERS

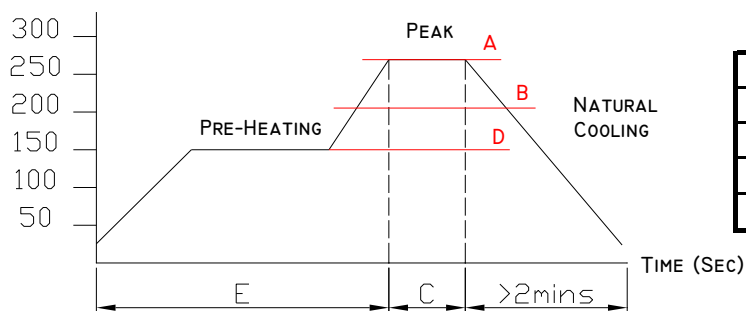
1	2	3	4	5	6	7	8	9	10	11	12
E	S	P	A	1	7	7	0	X	X	X	X
<u>Serial Codes</u>			<u>Size</u>				<u>Inductance Code</u>				

CONNECTIONS**RECOMMENDED LAYOUT**

- ⊙ Inductor Contents ONE (1) Set(s) of Coil
- ⊙ DC/AC Current Shall Be Introduced By Any One of Two Pads

RECOMMENDED SOLDERING TEMP. GRAPH

TEMPERATURE (°C)



A	260°C
B	230°C
C	10 Sec
D	150°C
E	60~240 Sec

ITEM P/N	ESPA-1770-SERIES	TEST INSTRUMENT	Zentech-3305 / Zentech502BC
PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V

ELECTRICAL CHARACTERISTICS

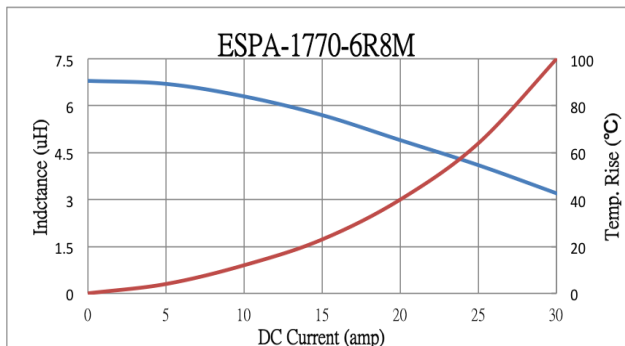
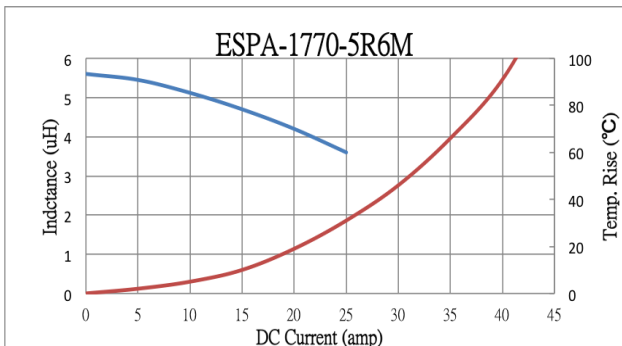
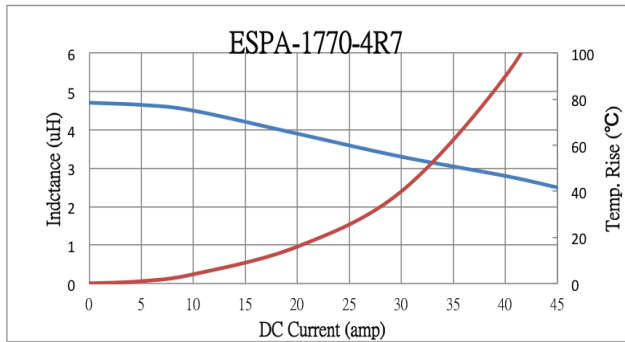
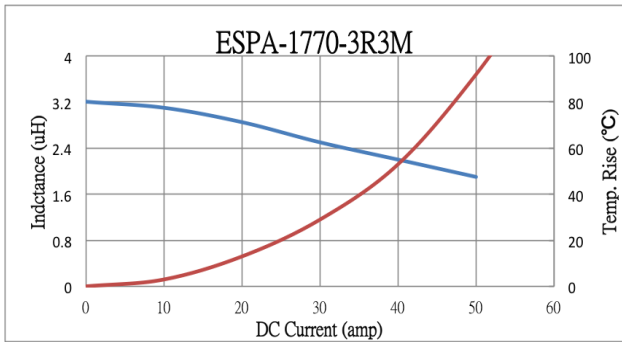
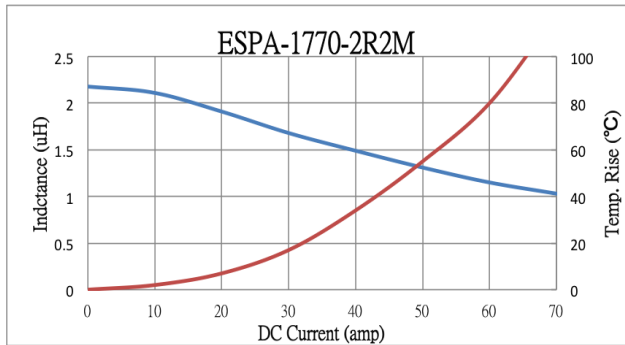
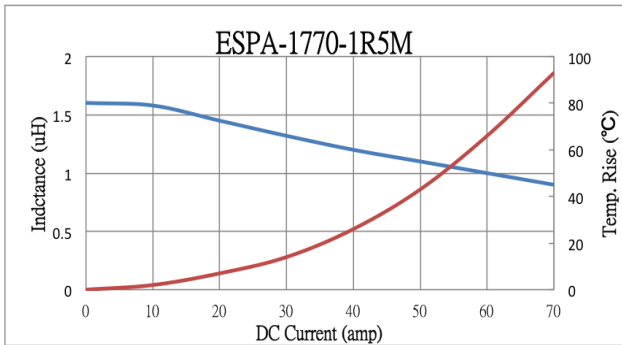
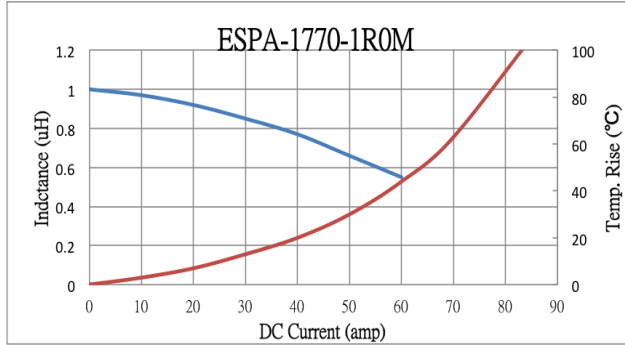
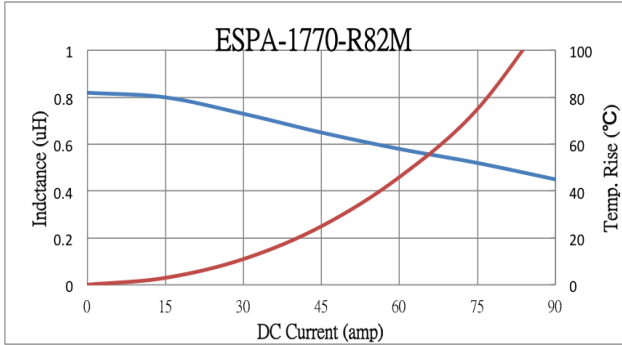
P/N	L0 Inductance $\mu\text{H} \pm 20\%$ @0A	DCR (m Ω)		Heat Rating Current	Saturation Current
		[Typical]	[Max]	Idc (AMP) Typical	Isat (AMP) Typical
ESPA-1770-R82M	0.82	0.98	1.08	56.5	45
ESPA-1770-1R0M	1.00	1.21	1.27	55.5	32
ESPA-1770-1R5M	1.50	1.54	1.62	48	31
ESPA-1770-2R2M	2.20	1.85	1.98	43.5	28
ESPA-1770-3R3M	3.30	2.79	2.93	35	27
ESP1-1770-4R7M	4.70	3.98	4.18	30	21
ESPA-1770-5R6M	5.60	4.23	4.44	28	21
ESPA-1770-6R8M	6.80	5.86	6.15	22.5	18.5
ESPA-1770-8R2M	8.20	7.71	8.10	21	18
ESPA-1770-100M	10.0	8.89	9.33	19	17
ESPA-1770-150M	15.0	13.7	14.4	14	12
ESPA-1770-220M	22.0	20.0	21.0	12	9.5
ESPA-1770-330M	33.0	35.1	37.0	10.7	9
ESPA-1770-470M	47.0	40.7	42.7	8.7	8.6
ESPA-1700-560M	56.0	55.0	57.8	7.2	4.2
ESPA-1770-680M	68.0	72.1	75.7	6.1	4.5
ESPA-1770-820M	82.0	87.3	91.7	5.5	4.5
ESPA-1770-101M	100.0	###	110.0	5.0	4.0

- ⊙ All test Data is referenced to 25°C ambient
- ⊙ Typical Heat Rating DC Current would cause an approximately ΔT of 40°C
- ⊙ Typical Saturation DC Current would cause Lo to drop approximately 30%
- ⊙ Operation Temperature Range : -55°C ~ 125°C
- ⊙ The Part temperature (ambient + ΔT) should not exceed 125°C under worst case operating conditions.
- ⊙ Circuit design, component placement, PWB trace size and thickness, airflow and other cooling provisions all effect the part temperature. Part temperature should be verified in the end application.

CHARACTERISTICS



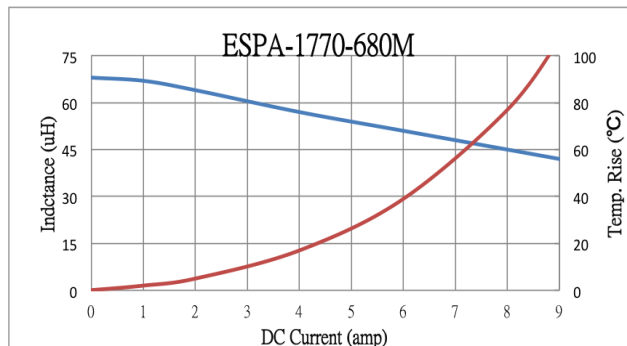
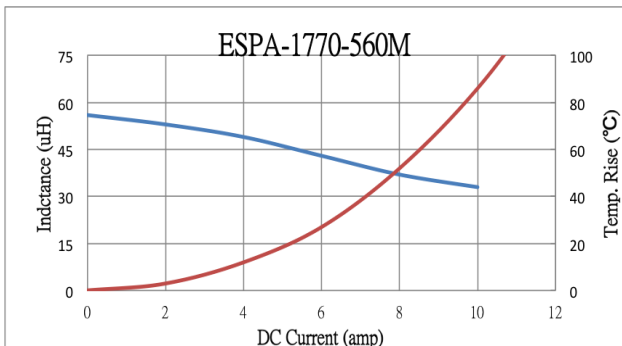
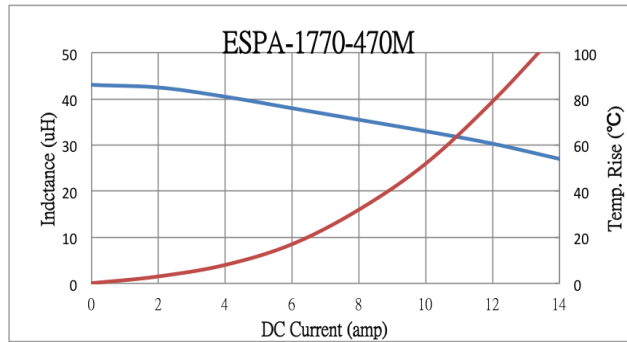
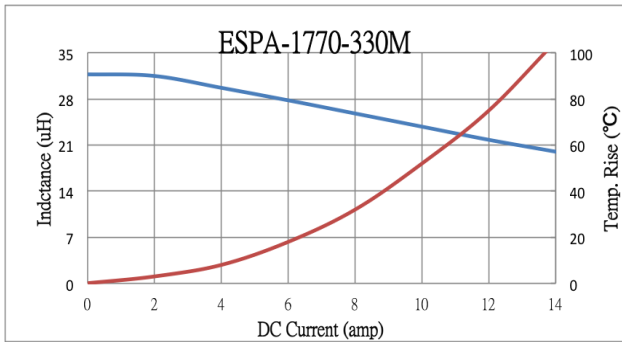
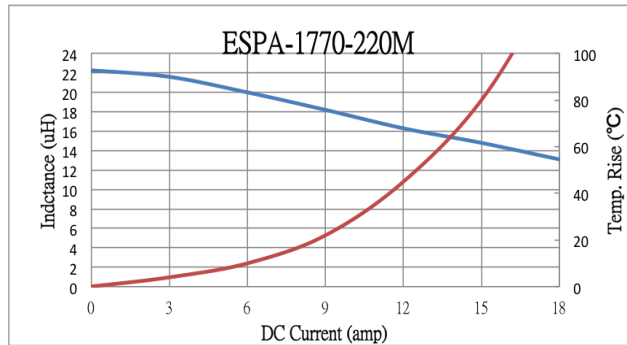
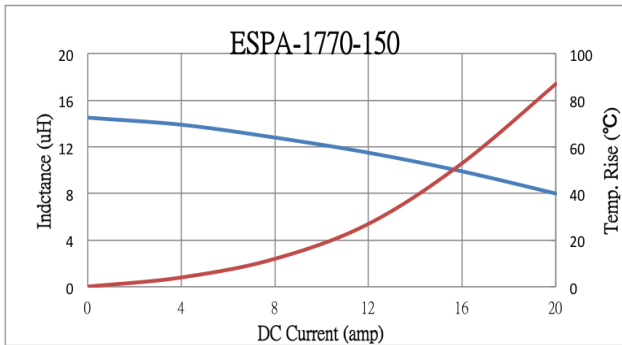
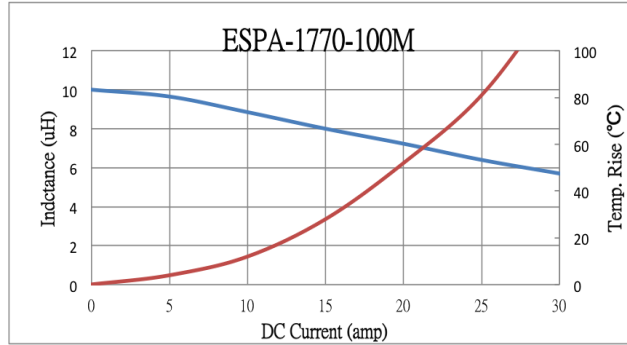
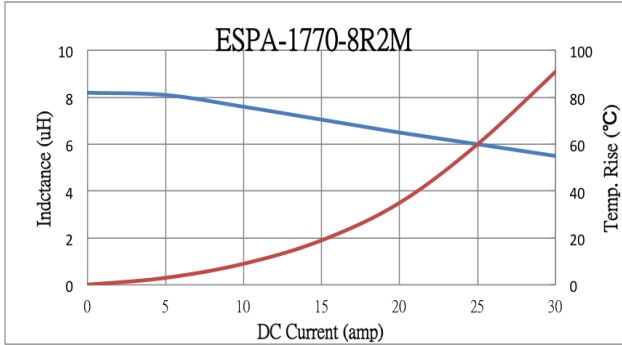
ITEM P/N	ESPA-1770-SERIES	TEST INSTRUMENT	Zentech-3305 / Zentech502BC
PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V



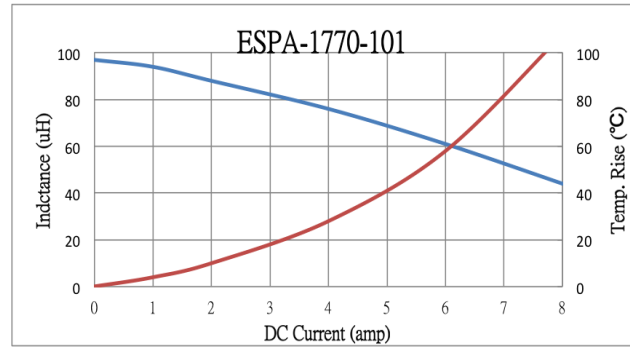
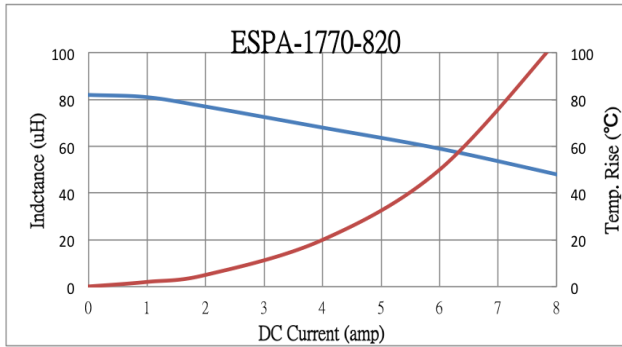
CHARACTERISTICS



ITEM P/N	ESPA-1770-SERIES	TEST INSTRUMENT	Zentech-3305 / Zentech502BC
PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V



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PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V

MECHANICAL RELIABILITY

TEST	Specification & Requirement	Method Used
Solderability	The surface of terminal/pin tested shall be covered with new solder by 95%	Solder heat proof: Preheating: 180 ±10°C 90 seconds Soldering: 255 ±5°C for 3 ±1 sec
Shock	Inductance change within ± 5% Without mechanical damage	Drop down with 981m/s2 (100G) shock Attitude upon a rubber block method shock testing machinem, 3 tests.
Vibration	Inductance change within ± 5% Without mechanical damage	Vibration frequency: 10Hz to 55Hz to 10Hz 60 seconds cycle Vibration time: 2 hours

ENDURANCE RELIABILITY

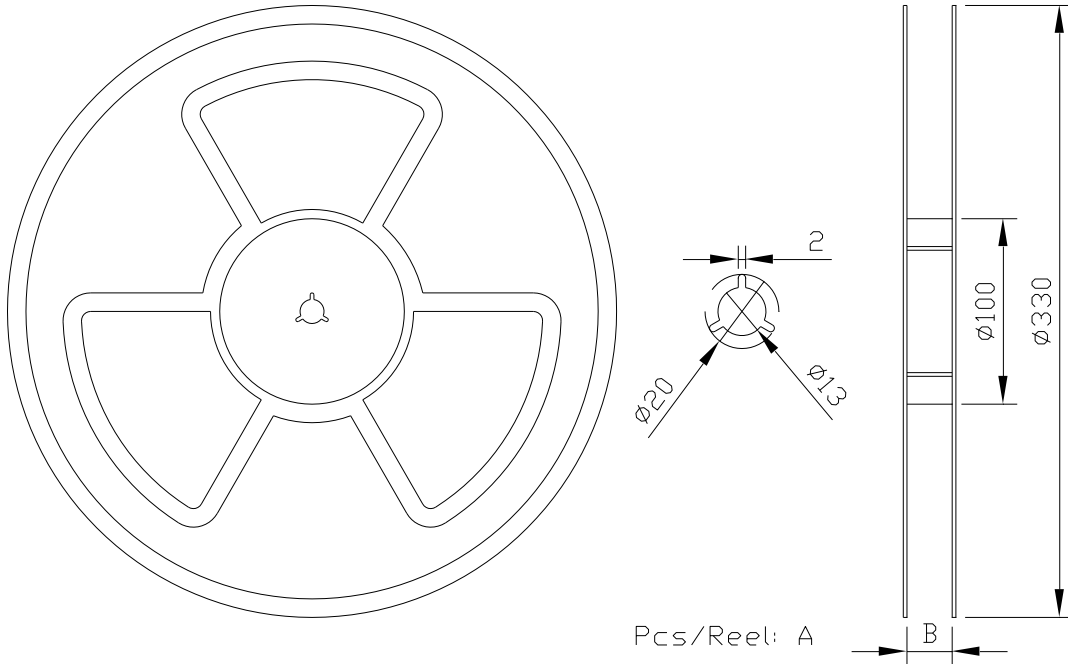
TEST	Specification & Requirement	Method Used
Thermal Shock	Inductance change within ± 5% Without mechanical damage	-55°C, (30 mins) -> room temp. (5 mins) -> 125°C, (30 mins) -> room temp. (5 mins) 100 cycles
Heat Resistance	Inductance change within ± 5% Without mechanical damage	Apply IDC current @ 85°C ambient Duration: 1000 hrs
Humidity Resistance	Inductance change within ± 5% Without mechanical damage	Apply IDC current @ 60°C ambient Humidity: 90~95% Duration: 1000 hrs
Low Temp. Storing	Inductance change within ± 5% Without mechanical damage	Storing Temp. -55 ±2 °C for total 1,000 +4/-0 hours
High Temp. Storing	Inductance change within ± 5% Without mechanical damage	Storing Temp. 125 ±2 °C for total 1,000 +4/-0 hours

PACKING FOR SMD

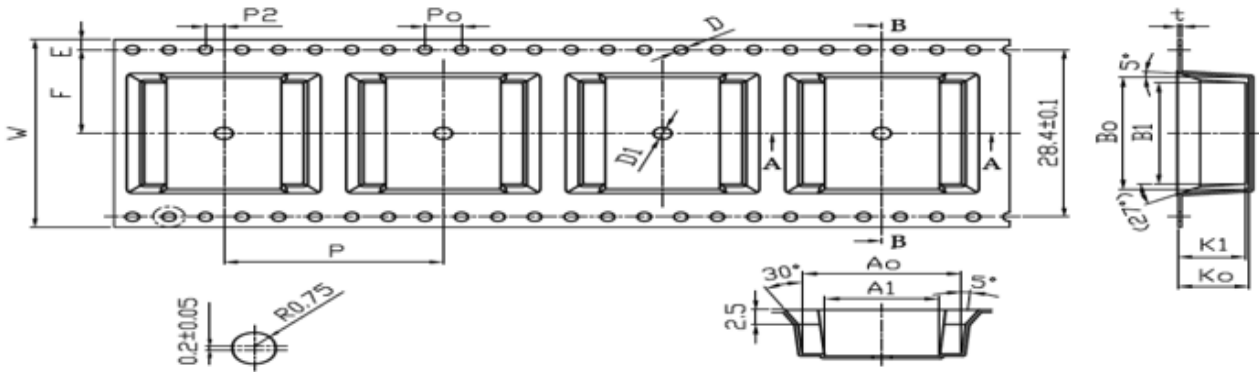
**RoHS
COMPLIANT**

ITEM P/N	ESPA-1770-SERIES	TEST INSTRUMENT	Zentech-3305 / Zentech502BC
PRODUCT	SMD Inductor	TEST FREQUENCY	100 kHz / 1.0V

CARRIERTAPEING REEL & CARRIER MATERIALS (PAPER PLASTICS) UNIT : (mm)



A	B	Ao	Bo	Ko
150	32	17.7	19.4	7.9



W	P
32	24

